

INFORMATION DISCLOSURE STATEMENT PTO-1449			ATTY. DOCKET NO. 07783-0002 CPUS10		SERIAL NO. <i>10/812,697</i> Not Yet Assigned	
			APPLICANTS: RONG, Chang-Liang, et al.			
			FILING DATE: March 29, 2004		GROUP: 2873	
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						YES	NO
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	2,340,683	Nat'l Entry Dt 2/14/2001	Canada (Schmidt, F. G.)			<input checked="" type="checkbox"/>	<input type="checkbox"/>
	EP 1065553	Pub Date 01/03/2001	Europe (Ogawa)			<input type="checkbox"/>	<input type="checkbox"/>
	EP 0990942	Pub Date 04/05/2000	Europe (Yamanaka)			<input type="checkbox"/>	<input type="checkbox"/>
	EP 1195603	Pub Date 04/10/2002	Europe (Kawai)			<input type="checkbox"/>	<input type="checkbox"/>
	JP 6242423	Pub Date 09/02/1994	Japan (Nakai Yuichi) (English abstract included)			<input type="checkbox"/>	<input checked="" type="checkbox"/>
	JP 64-86116	Pub Date 03/30/1989	Japan (Osamu et al) (English abstract included)			<input type="checkbox"/>	<input checked="" type="checkbox"/>
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EXAMINER	JACK DINH	DATE CONSIDERED	11/01/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.